

Document Title**1M x 16 bit Super Low Power and Low Voltage Full CMOS RAM****Revision History**

| Revision No. | History | Draft date | Remark |
|--------------|---|------------------------------|-------------|
| 0.0 | Initial Draft | Dec,08 th , 2008 | Preliminary |
| 0.1 | Revised Load Condition Revised I/O power (1.7V to VCC → 2.7V to VCC) Revised VIH (VCC-0.4 → 0.8VCCQ) Revised VIL (0.4 → 0.2VCCQ) | Jul. 3 rd , 2009 | Preliminary |
| 0.2 | Revised ISB1 (110uA → 100uA) Revised ISB0c (110uA → 100uA) Revised ISB0b (100uA → 80uA) Revised ISB0a (90uA → 70uA) | Nov. 25 th , 2009 | Preliminary |
| 0.3 | Correct typo in Array Refresh Area of Mode Register Set | Feb. 3 rd , 2010 | Preliminary |
| 0.4 | Removed Page Write Operation | Jul. 21 st , 2010 | Final |

1M x 16 bit Super Low Power and Low Voltage Full CMOS RAM

FEATURES

- Process Technology : Full CMOS
- Organization : 1M x 16
- Power Supply Voltage : 2.7~3.3V
- Three state output and TTL Compatible
- Separated I/O power(VCCQ) & Core power(VCC)
- Operating Temperature Ranges:
 - Special (-10°C to +60°C)
 - Commercial (0°C to +70°C)
 - Extended (-25°C to +85°C)
 - Industrial (-40°C to +85°C)

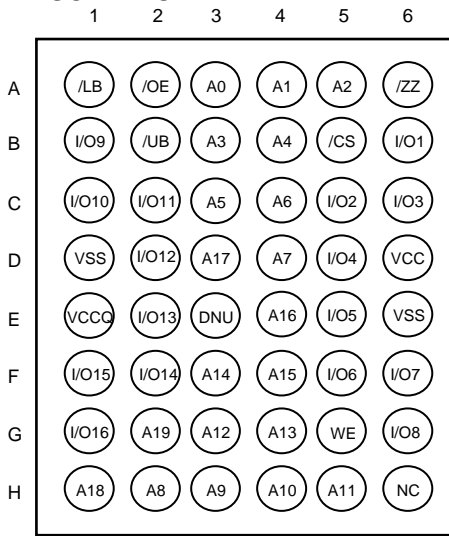
- Package Type : 48-FBGA-6.00x8.00 mm²
FMP1617DAx-HxxX : Pb-Free & Halogen Free
- Low Power & Page Modes
 - FMP1617DA1 : support the PASR/DPD function
 - FMP1617DA2 : support the Direct DPD function
 - FMP1617DA4 : support the PASR/DPD/PAGE function
 - FMP1617DA5 : support the Direct DPD/PAGE function
- Page read/write operation by 16 words (FMP1617DA4, FMP1617DA5)
- DPD mode by using MRS only (FMP1617DA1, FMP1617DA4)
- Direct DPD mode when /ZZ goes low (FMP1617DA2, FMP1617DA5)

PRODUCT FAMILY

| Product Family | Operating Voltage (V) | | | Speed | Power Dissipation | | | | | |
|------------------------------------|-----------------------|------|------|--------------|-------------------|------|--------------|------|-----------------------------|-------|
| | Min. | Typ. | Max. | | ICC1 | | ICC2 | | ISB1 (CMOS Standby Current) | |
| | | | | | f = 1MHz | | f = fmax | | | |
| | | | | | Typ. | Max. | Typ. | Max. | Typ. | Max. |
| FMP1617DAx-H60E FMP1617DAx-H70E | 2.7 | 3.0 | 3.3 | 60ns 70ns | 1.5mA | 3mA | 15mA 12mA | 20mA | 70uA | 100uA |

1. Typical values are included for reference only and are not guaranteed or tested. Typical values are measured at Vcc = Vcc (typ) and T_A = 25°C.
 2. H=FBGA(Pb-Free & Halogen Free), W=WAFER
 3. Operating Temperature Range: S (-10°C~60°C), C(0°C~70°C), E(-25°C~85°C), I (-40°C~85°C)

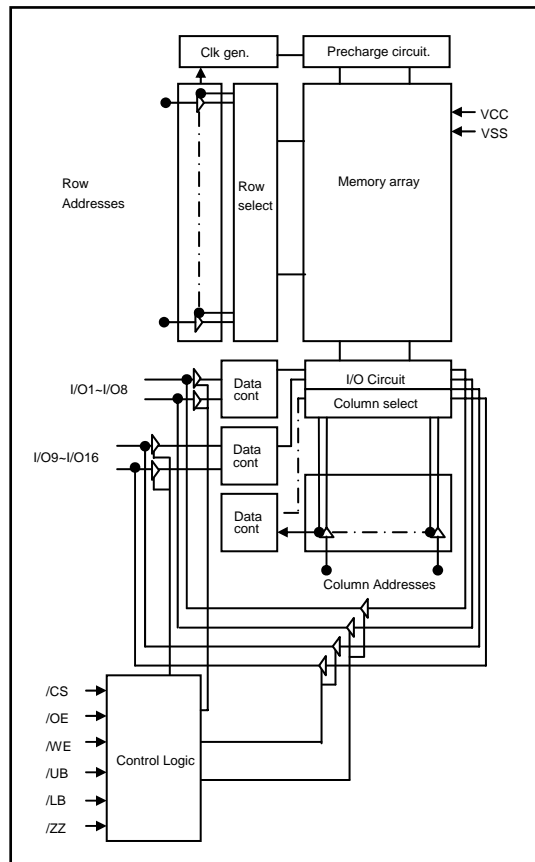
PIN DESCRIPTION



48-FBGA : Top View(Ball Down)

| Name | Function | Name | Function |
|------------|---------------------|------|---------------------|
| /ZZ | Low Power Modes | VCC | Core Power |
| /CS | Chip Select Input | VCCQ | I/O Power |
| /OE | Output Enable Input | VSS | Ground |
| /WE | Write Enable Input | /UB | Upper Byte(I/O9~16) |
| A0~A19 | Address Inputs | /LB | Lower Byte(I/O 1~8) |
| I/O1~I/O16 | Data Inputs/Outputs | DNU | Do Not Use |

FUNCTIONAL BLOCK DIAGRAM



PRODUCT LIST

| Part Name | Function |
|-----------------|---------------------------|
| FMP1617DAx-H60E | 60ns, VCC=3.0V, VCCQ=3.0V |
| FMP1617DAx-H70E | 70ns, VCC=3.0V, VCCQ=3.0V |

1. H=FBGA(Pb-Free & Halogen Free), W=WAFER

2. Operating Temperature Range: S (-10°C~60°C), C(0°C~70°C), E(-25°C~85°C), I (-40°C~85°C)

FUNCTIONAL DESCRIPTION

| /CS | /ZZ | /OE | /WE | /LB | /UB | I/O1-8 | I/O9-16 | Mode | Power |
|------------------|-----|------------------|------------------|------------------|------------------|--------|---------|------------------|--------------------------------|
| H | H | X ⁽¹⁾ | X ⁽¹⁾ | X ⁽¹⁾ | X ⁽¹⁾ | High-Z | High-Z | Deselected | Standby |
| X ⁽¹⁾ | L | X ⁽¹⁾ | X ⁽¹⁾ | X ⁽¹⁾ | X ⁽¹⁾ | High-Z | High-Z | Deselected | Direct DPD ⁽²⁾ |
| H | L | X ⁽¹⁾ | X ⁽¹⁾ | X ⁽¹⁾ | X ⁽¹⁾ | High-Z | High-Z | Deselected | Low Power Modes ⁽³⁾ |
| X ⁽¹⁾ | H | X ⁽¹⁾ | X ⁽¹⁾ | H | H | High-Z | High-Z | Deselected | Standby |
| L | H | H | H | L | X ⁽¹⁾ | High-Z | High-Z | Output Disabled | Active |
| | H | H | H | X ⁽¹⁾ | L | High-Z | High-Z | Output Disabled | Active |
| L | H | L | H | L | H | Dout | High-Z | Lower Byte Read | Active |
| | | | | H | L | High-Z | Dout | Upper Byte Read | Active |
| | | | | L | L | Dout | Dout | Word Read | Active |
| | | X ⁽¹⁾ | L | L | H | Din | High-Z | Lower Byte Write | Active |
| | | | | H | L | High-Z | Din | Upper Byte Write | Active |
| | | | | L | L | Din | Din | Word Write | Active |

1. X means don't care.(Must be low or high state)

2. In case of FMP1617DA2 & FMP1617DA5 product

3. In case of FMP1617DA1 & FMP1617DA4 product

ABSOLUTE MAXIMUM RATINGS⁽¹⁾

| Item | Symbol | Ratings | Unit |
|---------------------------------------|-----------|------------------|------|
| Voltage on any pin relative to VSS | VIN, VOUT | -0.5 to VCC+0.3V | V |
| Voltage on VCC supply relative to VSS | VCC | -0.2 to 3.6 | V |
| Power Dissipation | PD | 1.0 | W |
| Storage temperature | TSTG | -65 to 150 | °C |

1. Stresses greater than those listed under "Absolute Maximum Ratings" may cause permanent damage to the device. Functional operation should be restricted to recommended operating condition. Exposure to absolute maximum rating conditions for extended periods may affect reliability.

RECOMMENDED DC OPERATING CONDITIONS

| Item | Symbol | FMP1617DAx | | | Unit |
|------------------------------------|--------|---------------------|------|------------------------|------|
| | | Min | Typ | Max | |
| Supply voltage | VCC | 2.7 | 3.0V | 3.3 | V |
| I/O operating voltage (VCCQ ≤ VCC) | VCCQ | 2.7 | 3.0V | 3.3 | V |
| Ground | VSS | 0 | 0 | 0 | V |
| Input high voltage | VIH | 0.8VCCQ | VCCQ | VCC+0.2 ⁽¹⁾ | V |
| Input low voltage | VIL | -0.2 ⁽²⁾ | 0 | 0.2VCCQ | V |

Note :

1. Overshoot : Vcc+1.0V in case of pulse width ≤20ns.

2. Undershoot : -1.0V in case of pulse width ≤20ns.

3. Overshoot and undershoot are sampled, not 100% tested.

CAPACITANCE¹⁾ (f=1MHz, T_A=25°C)

| Item | Symbol | Test Condition | Min | Max | Unit |
|--------------------------|--------|----------------|-----|-----|------|
| Input capacitance | CIN | VIN=0V | - | 8 | pF |
| Input/Output capacitance | CIO | VIO=0V | - | 8 | pF |

1. Capacitance is sampled, not 100% tested.

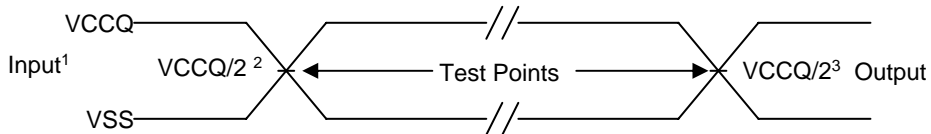
DC AND OPERATING CHARACTERISTICS

| Item | Symbol | Test Conditions | Min | Max | Unit |
|---------------------------|--------|--|---------|---------|------|
| Input leakage current | ILI | VIN=VSS to VCC | -1 | 1 | uA |
| Output leakage current | ILO | /CS=VIH, /ZZ=VIH, /OE=VIH or /WE=VIL, VIO=VSS to VCC | -1 | 1 | uA |
| Average operating current | ICC1 | Cycle time=1us, 100%duty, IIO=0mA, /CS≤0.2V, /ZZ=VIH, VIN≤0.2V or VIN≥VCC-0.2V | - | 3 | mA |
| | ICC2 | Cycle time=Min, IIO=0mA, 100% duty, /CS=VIL, /ZZ=VIH, VIN=VIL or VIH | - | 20 | mA |
| Output low voltage | VOL | IOL=0.5mA | | 0.2VCCQ | V |
| Output high voltage | VOH | IOH=-0.5mA | 0.8VCCQ | | V |
| Standby Current(TTL) | ISB | /CS=VIH, /ZZ=VIH, Other inputs=VIH or VIL | - | 0.3 | mA |
| Standby Current(CMOS) | ISB1 | /CS≥VCC-0.2V, /ZZ≥VCC-0.2V, Other inputs=0~VCC | - | 100 | uA |
| Low Power Modes | ISB0 | /ZZ≤0.2V, Other inputs=0~VCC, No refresh(DPD) | - | 10 | uA |
| | ISB0a | /ZZ≤0.2V, Other inputs=0~VCC, ¼ refresh area selection | - | 70 | uA |
| | ISB0b | /ZZ≤0.2V, Other inputs=0~VCC, ½ refresh area selection | - | 80 | uA |
| | ISB0c | /ZZ≤0.2V, Other inputs=0~VCC, All refresh area selection | - | 100 | uA |

Operating Range

| Device | Range | Ambient Temperature | VCC | VCCQ |
|-----------------|------------|---------------------|--------------|-------------|
| FMP1617DAX-XxxS | Special | -10°C to +60°C | 2.7V to 3.3V | 2.7V to VCC |
| FMP1617DAX-XxxC | Commercial | 0°C to +70°C | | |
| FMP1617DAX-XxxE | Extended | -25°C to +85°C | | |
| FMP1617DAX-XxxI | Industrial | -40°C to +85°C | | |

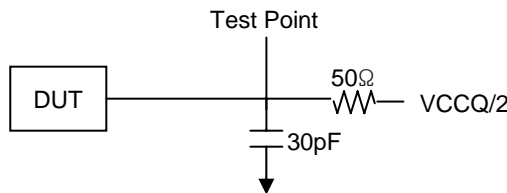
AC Input/Output Reference Waveform



NOTE:

1. AC test inputs are driven at VCCQ for a logic 1 and VSS for a logic 0. Input rise and fall times (10% to 90%) < 1.6ns.
2. Input timing begins at VCCQ/2.
3. Output timing ends at VCCQ/2.

AC Output Load Circuit



AC CHARACTERISTICS(VCC=2.7V~3.3V)

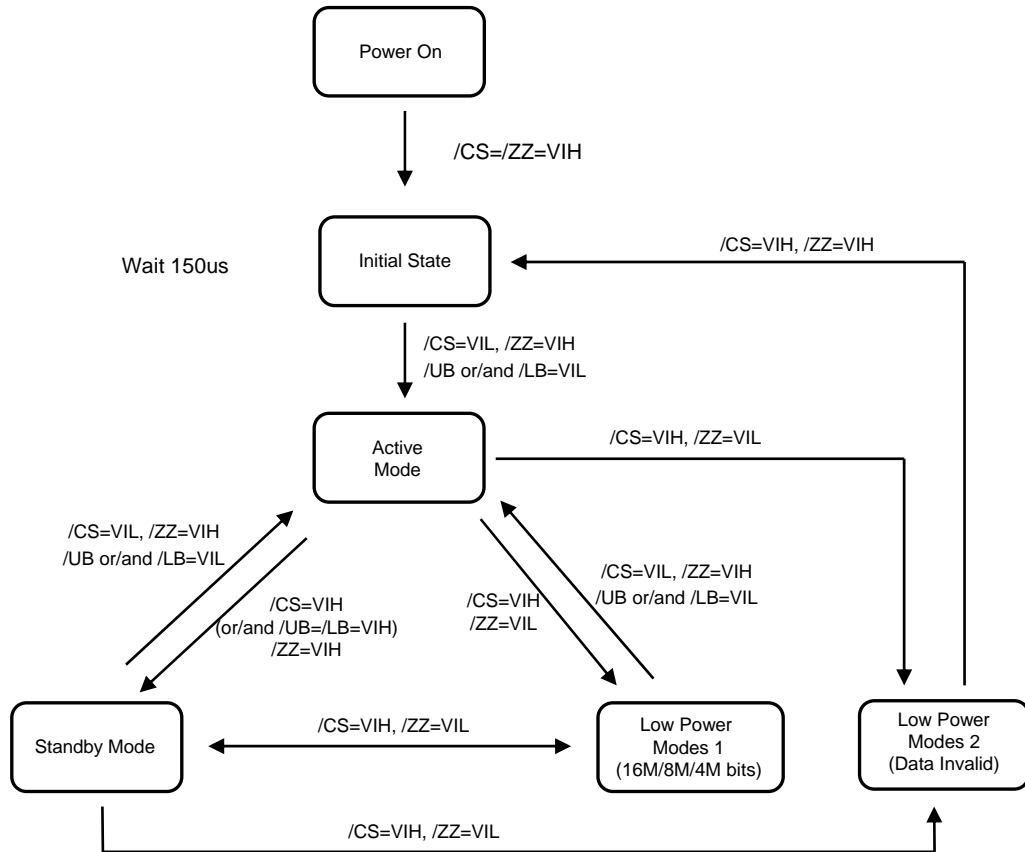
| Parameter List | | Symbol | Speed Bins | | | | Units |
|----------------------|------------------------------------|--------|------------|-----|------|-----|-------|
| | | | 60ns | | 70ns | | |
| | | | Min | Max | Min | Max | |
| Read | Read Cycle Time | tRC | 60 | 20k | 70 | 20k | ns |
| | Address Access Time | tAA | - | 60 | - | 70 | ns |
| | Chip Select to Output | tCO | - | 60 | - | 70 | ns |
| | Output Enable to Valid Output | tOE | - | 25 | - | 25 | ns |
| | /UB, /LB Access Time | tBA | - | 60 | - | 70 | ns |
| | Chip Select to Low-Z Output | tLZ | 10 | - | 10 | - | ns |
| | /UB, /LB Enable to Low-Z Output | tBLZ | 10 | - | 10 | - | ns |
| | Output Enable to Low-Z Output | tOLZ | 5 | - | 5 | - | ns |
| | Chip Disable to High- Z Output | tHZ | 0 | 5 | 0 | 5 | ns |
| | /UB, /LB Disable to High- Z Output | tBHZ | 0 | 5 | 0 | 5 | ns |
| | Output Disable to High- Z Output | tOHZ | 0 | 5 | 0 | 5 | ns |
| | Output Hold from Address Change | tOH | 5 | - | 5 | - | ns |
| Write | Write Cycle Time | tWC | 60 | 20k | 70 | 20k | ns |
| | Chip Select to End of Write | tCW | 50 | - | 60 | - | ns |
| | Address Set-up Time | tAS | 0 | - | 0 | - | ns |
| | Address Valid to End of Write | tAW | 50 | - | 60 | - | ns |
| | /UB, /LB Valid to End of Write | tBW | 50 | - | 60 | - | ns |
| | Write Pulse Width | tWP | 50 | - | 50 | - | ns |
| | Write Recovery Time | tWR | 0 | - | 0 | - | ns |
| | Write to Output High-Z | tWHZ | 0 | 5 | 0 | 5 | ns |
| | Data to Write Time Overlap | tDW | 20 | - | 20 | - | ns |
| | Data Hold from Write Time | tDH | 0 | - | 0 | - | ns |
| | End Write to Output Low-Z | tOW | 5 | - | 5 | - | ns |
| Page | Page Mode Cycle Time | tPC | 20 | - | 25 | - | ns |
| | Page Mode Address Access Time | tPAA | - | 20 | - | 25 | ns |
| | Maximum Cycle Time | tMRC | - | 20k | - | 20k | ns |
| /CS High Pulse Width | | tCP | 10 | - | 10 | - | ns |

1. /CS High Pulse Width is defined by /CS or (/UB and /LB) because /UB & /LB can make standby mode when /UB=High and /LB=High.

Power Up Sequence

1. Apply Power
2. Maintain stable power for a minimum of 150us with /CS=/ZZ=VIH

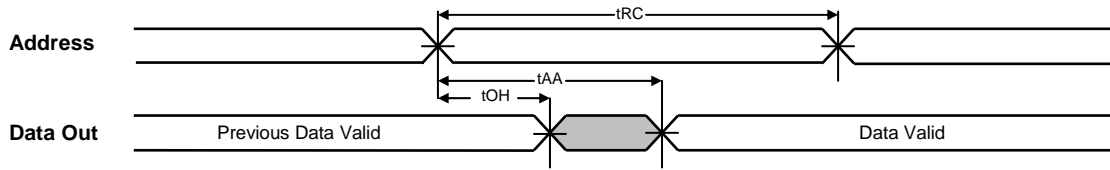
Standby Mode State machines



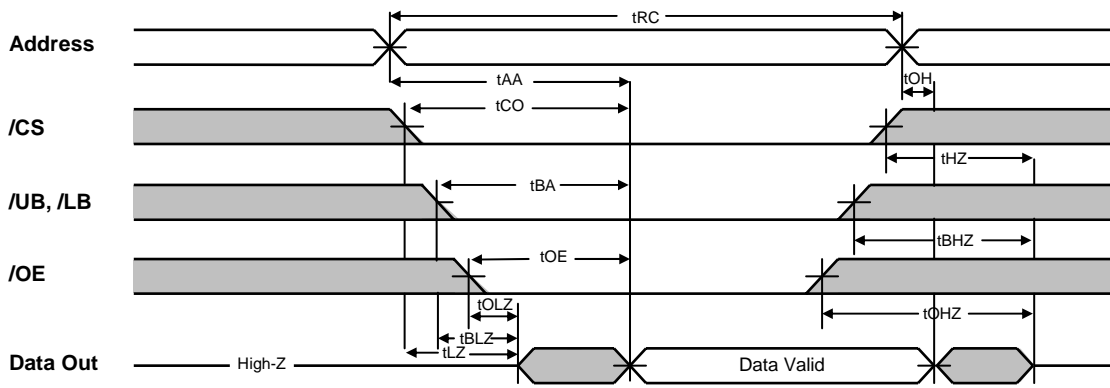
Standby Mode Characteristics

| Mode | Memory Cell Data | Standby Current(uA) | Wait Time(us) |
|-----------------|------------------|---------------------|---------------|
| Standby | Valid | 100 (ISB1) | 0 |
| Low Power Modes | Invalid | 10 (ISB0) | 150 |
| | ¼ valid | 70 (ISB0a) | 0 |
| | ½ valid | 80 (ISB0b) | 0 |
| | valid | 100 (ISB0c) | 0 |

READ CYCLE (1) (Address controlled, /CS=/OE=VIL, /ZZ=/WE=VIH, /UB or/and /LB=VIL)

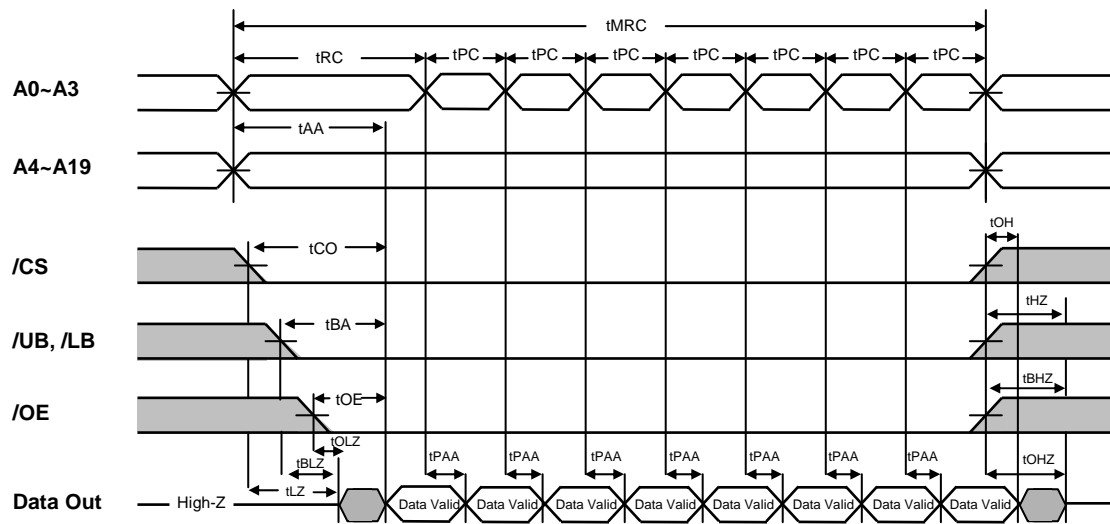


READ CYCLE (2) (/ZZ=/WE=VIH)



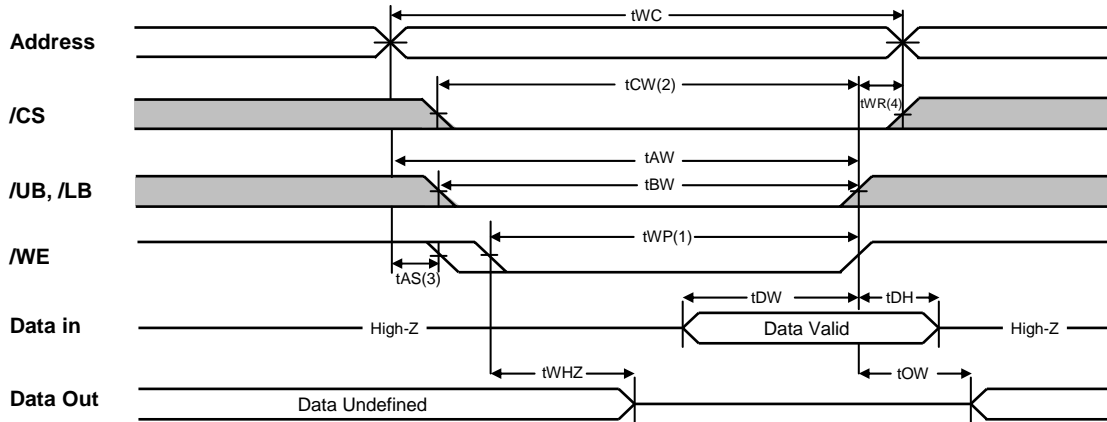
1. tHZ and tOHZ are defined as the time at which the outputs achieve the open circuit conditions and are not referenced to output voltage levels.
2. At any given temperature and voltage condition, tHZ(Max.) is less than tLZ(Min.) both for a given device and from device to device interconnection.
3. Do not access device with cycle timing shorter than tRC(tWC) for continuous periods > 20us.

PAGE READ CYCLE (/ZZ=/WE=VIH, 16 words access)

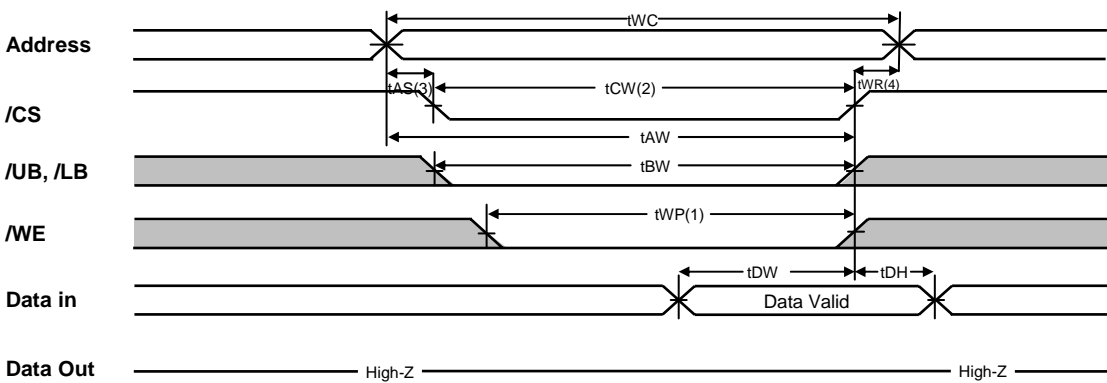


1. tHZ and tOHZ are defined as the time at which the outputs achieve the open circuit conditions and are not referenced to output voltage levels.
2. At any given temperature and voltage condition, tHZ(Max.) is less than tLZ(Min.) both for a given device and from device to device interconnection.
3. Do not access device with cycle timing shorter than tRC(tWC) for continuous periods > 20us.
4. In case page address skew is over 3ns, tPAA will be out of spec.

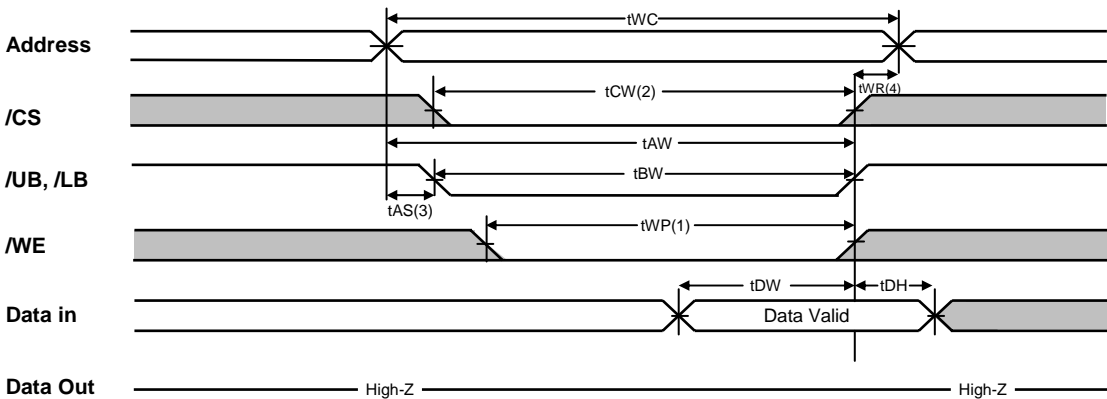
WRITE CYCLE (1) (*/WE controlled, /ZZ=VIH*)



WRITE CYCLE (2) (*/CS controlled, /ZZ=/WE=VIH*)



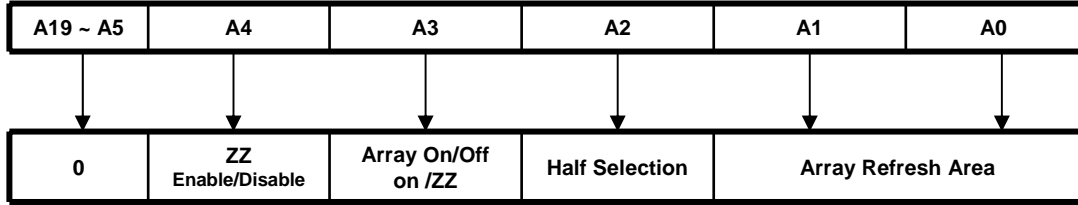
WRITE CYCLE (3) (*/UB, /LB controlled, /ZZ=VIH*)



1. A write occurs during the overlap (t_{WP}) of low */CS* and */WE*. A write begins when */CS* goes low and */WE* goes low with asserting */UB* or */LB* for single byte operation or simultaneously asserting */UB* and */LB* for double byte operation. A write ends at the earliest transition when */CS* goes high and *WE* goes high. The t_{WP} is measured from the beginning of write to the end of write.
2. t_{CW} is measured from the */CS* going low to end of write.
3. t_{AS} is measured from the address valid to the beginning of write.
4. t_{WR} is measured from the end of write to the address change. t_{WR} applied in case a write ends as */CS* or */WE* going high.
5. Do not access device with cycle timing shorter than $t_{RC}(t_{WC})$ for continuous periods > 20 μ s.

LOW POWER MODES

1. Mode Register Set



/ZZ Enable/Disable

| A4 | Type |
|----|------------------------|
| 0 | Deep Power Down Enable |
| 1 | DPD Disable (Default) |

Note: If the register is written to enable the Deep Power Down, the part will go into Deep Power Down during the following time that /ZZ is driven low and there is no MRS update. When /ZZ is driven high, all of the register settings will return to default state for the part (i.e. full array refresh, Deep Power Down Disabled).

Array On/Off on /ZZ

| A3 | Type |
|----|--------------------------------------|
| 0 | Partial Array Refresh Mode (Default) |
| 1 | Reduced Memory Size Mode |

Note: The RMS(Reduced Memory Size) mode is enabled after /ZZ goes high and remains enabled after /ZZ goes high. To change to a different mode, the mode register will have to be rewritten.

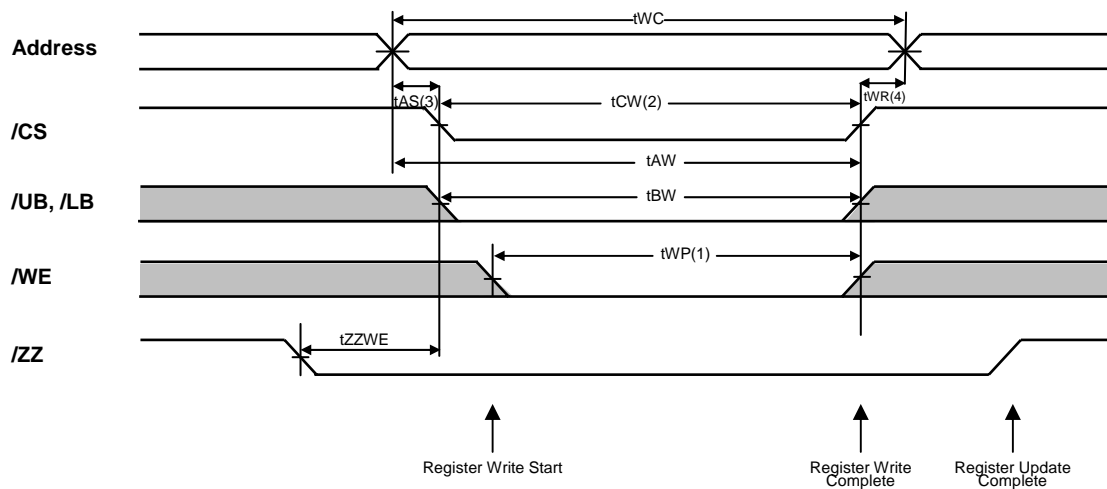
Half Selection (Top / Bottom)

| A2 | Type |
|----|------------------|
| 0 | Bottom (Default) |
| 1 | Top |

Array Refresh Area

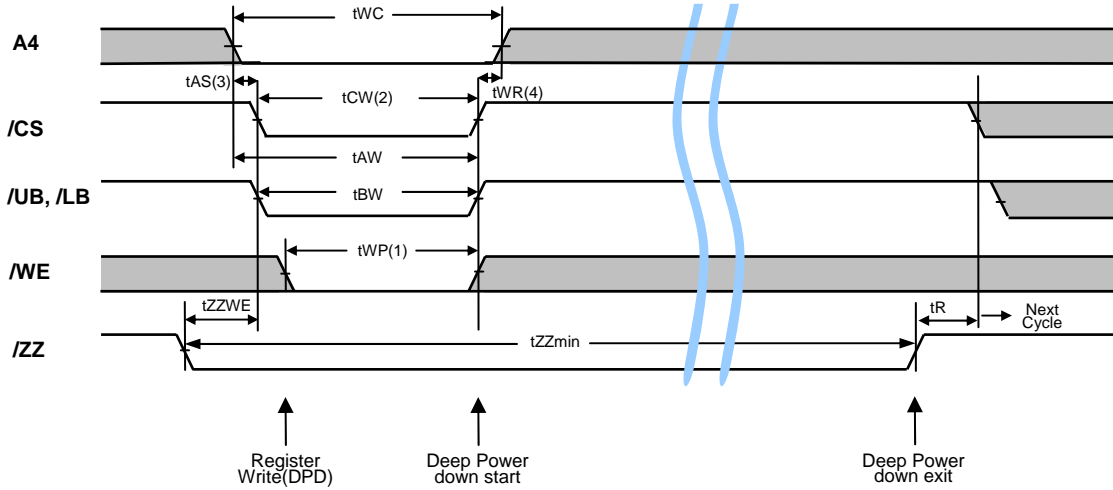
| A1 | A0 | Type |
|----|----|----------------------|
| 0 | 0 | Full Array (Default) |
| 0 | 1 | RFU |
| 1 | 0 | ½ Array |
| 1 | 1 | ¼ Array |

2. MRS Update



The register update take place on the rising edge of /ZZ. Once the register is updated, the next time /ZZ goes low, without any updates to the register starting within the tZZWE max time of 1us, the part will refresh the array selected. The data bus is a don't care When /ZZ is low during the register updates.

3. Deep Power Down Mode Entry/Exit



| Parameter | Description | Min | Max | Units |
|-------------------------------|----------------------------|-----|-----|-------|
| tZZWE | ZZ low to Write Enable Low | 0 | 1 | us |
| tR(Deep Power Down Mode only) | Operation Recovery Time | 150 | - | us |
| tZZmin | Low Power Mode Time | 10 | - | us |

4. Address Information

Partial Array Refresh Mode (A3=0, A4=1)

| A2 | A1,A0 | Refresh Section | Address | Size | Density |
|----|-------|-----------------|----------------|----------|---------|
| 0 | 11 | 1/4 | 00000h-3FFFFh | 256Kbx16 | 4Mb |
| 0 | 10 | 1/2 | 00000h-7FFFFh | 512Kbx16 | 8Mb |
| X | 00 | Full | 00000h-FFFFFFh | 1Mbx16 | 16Mb |
| 1 | 11 | 1/4 | C0000h-FFFFFFh | 256Kbx16 | 4Mb |
| 1 | 10 | 1/2 | 80000h-FFFFFFh | 512Kbx16 | 8Mb |

Reduced Memory Size Mode (A3=1, A4=1)

| A2 | A1,A0 | Refresh Section | Address | Size | Density |
|----|-------|-----------------|----------------|----------|---------|
| 0 | 11 | 1/4 | 00000h-3FFFFh | 256Kbx16 | 4Mb |
| 0 | 10 | 1/2 | 00000h-7FFFFh | 512Kbx16 | 8Mb |
| 1 | 11 | 1/4 | C0000h-FFFFFFh | 256Kbx16 | 4Mb |
| 1 | 10 | 1/2 | 80000h-FFFFFFh | 512Kbx16 | 8Mb |

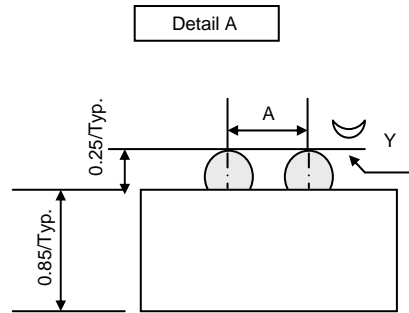
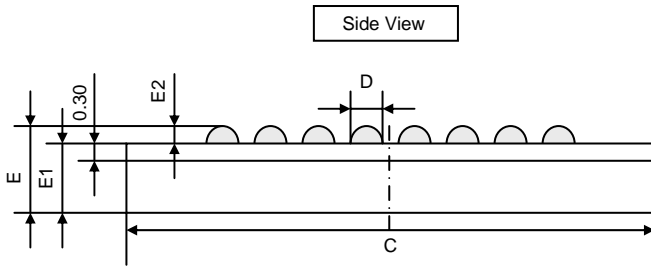
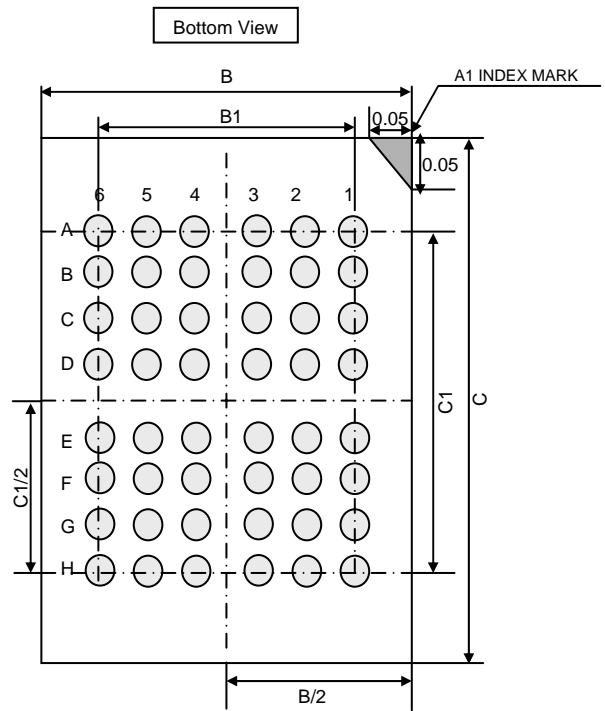
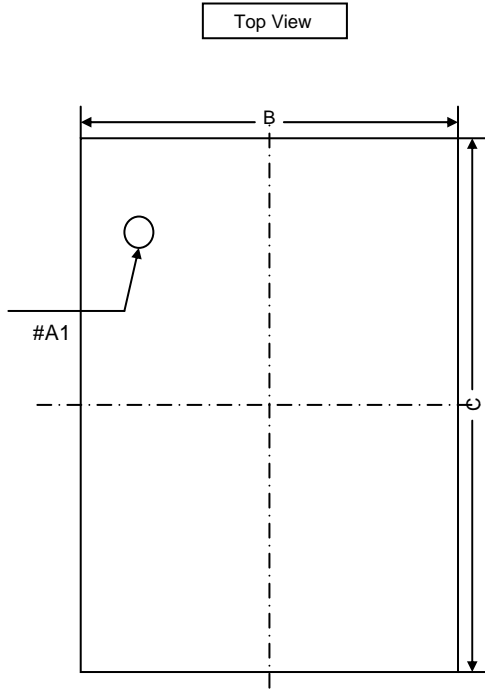
FMP1617DAx

CMOS LPRAM

PACKAGE DIMENSION

Unit : millimeters

48 BALL FINE PITCH BGA(0.75mm ball pitch)



| | Min | Typ | Max |
|----|------|------|------|
| - | | | |
| A | - | 0.75 | - |
| B | 5.90 | 6.00 | 6.10 |
| B1 | - | 3.75 | - |
| C | 7.90 | 8.00 | 8.10 |
| C1 | - | 5.25 | - |
| D | 0.30 | 0.35 | 0.40 |
| E | - | 1.10 | 1.20 |
| E1 | - | 0.85 | - |
| E2 | 0.20 | 0.25 | 0.30 |
| Y | - | - | 0.08 |

NOTES.

1. Bump counts : 48(8row x 6column)
2. Bump pitch : (x,y)=(0.75 x 0.75)(typ.)
3. All tolerance are +/-0.050 unless otherwise specified.
4. Typ : Typical
5. Y is coplanarity : 0.08(Max)